

November 2013

FQD3N60CTM_WS

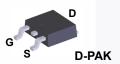
N-Channel QFET $^{\rm @}$ MOSFET 600 V, 2.4 A, 3.4 Ω

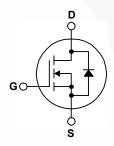
Features

- 2.4 A, 600 V, $R_{DS(on)}$ = 3.4 Ω (Max.) @ V_{GS} = 10 V, I_D = 1.2 A
- Low Gate Charge (Typ. 10.5 nC)
- Low Crss (Typ. 5 pF)
- · 100% Avalanche Tested

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQD3N60CTM_WS	Unit
V_{DSS}	Drain-Source Voltage		600	V
I _D	Drain Current - Continuous (T _C = 25°C)		2.4	A
	- Continuous (T _C = 100°C)		1.5	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	9.6	Α
V _{GSS}	Gate-Source Voltage		±30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	150	mJ
I _{AR}	Avalanche Current	(Note 1)	2.4	Α
E _{AR}	Repetitive Avalanche Energy (N		4.0	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns
P _D	Power Dissipation (T _C = 25°C)		50	W
ı D	- Derate above 25°C		0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C
'L			230	C

Thermal Characteristics

Symbol	Parameter	FQD3N60CTM_WS	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	110	°C/W

Package Marking and Ordering Information

Device Marking Device		Package	Reel Size	Tape Width	Quantity	
FQD3N60CS	FQD3N60CTM_WS	D-PAK	330 mm	16 mm	2500 units	

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	600			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C		0.6		V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			1	μА
I _{DSS}		V _{DS} = 480 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30V, V_{DS} = 0V$			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30V, V _{DS} = 0V	600		-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10V, I _D = 1.2A		2.8	3.4	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40V, I _D = 1.2A	\	3.5		S
C _{iss}	c Characteristics Input Capacitance	V = 25V V = 0V		435	565	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ f = 1.0MHz		45	60	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0WHZ		5	8	pF
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V - 200 V I - 2 A		12	34	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_{D} = 3 \text{ A},$ $R_{G} = 25 \Omega$		30	70	ns
t _{d(off)}	Turn-Off Delay Time	11G - 20 sz		35	80	ns
t _f	Turn-Off Fall Time	(Note 4)		35	80	ns
Qg	Total Gate Charge	V _{DS} = 480 V, I _D = 3 A,	//	10.5	14	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V	-	2.1		nC
Q _{gd}	Gate-Drain Charge	(Note 4)		4.5		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Dic				3	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Forward Current			12	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0V, I _S = 2.4A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _S = 3A		260		ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt =100A/μs		1.6		μC

NOTES:

^{1.} Repetitive Rating: Pulse width limited by maximum junction temperature.

^{2.} I $_{AS}$ = 2.4 A, V $_{DD}$ = 50 V, L=47 mH, R $_{G}$ = 25 Ω , starting T $_{J}$ = 25°C.

^{3.} $I_{SD} \le 3$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, starting T_J = 25°C.

^{4.} Essentially independent of operating temperature.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

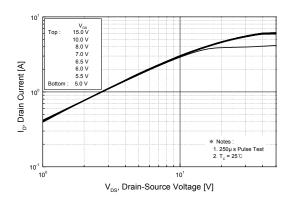


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

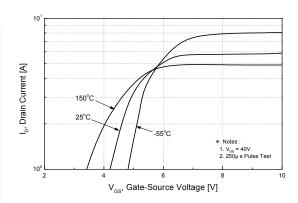


Figure 2. Transfer Characteristics

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

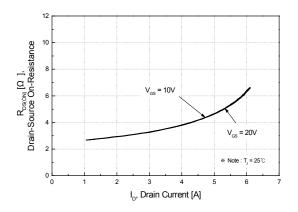


Figure 5. Capacitance Characteristics

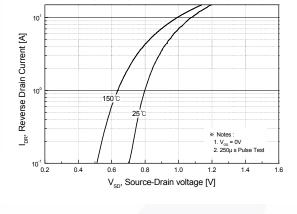
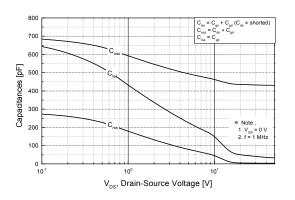
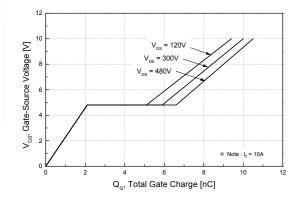


Figure 6. Gate Charge Characteristics





Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

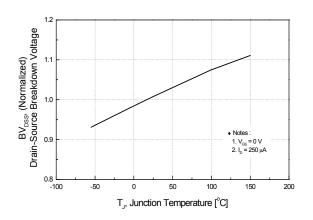


Figure 8. On-Resistance Variation vs. Temperature

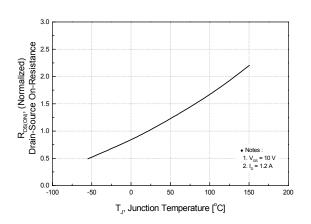
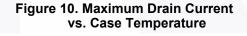
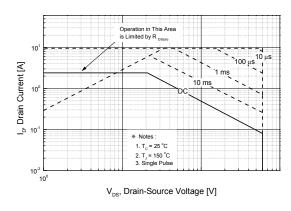


Figure 9. Maximum Safe Operating Area





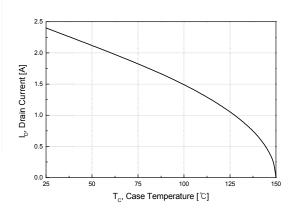


Figure 11. Transient Thermal Response Curve

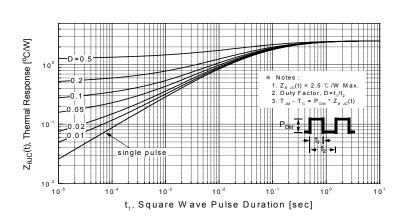


Figure 12. Gate Charge Test Circuit & Waveform

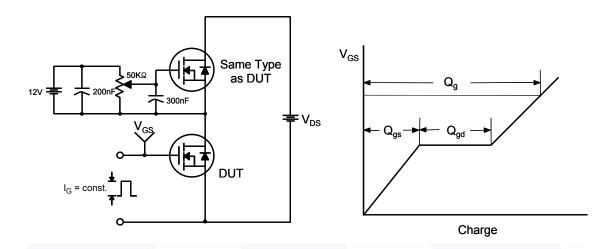


Figure 13. Resistive Switching Test Circuit & Waveforms

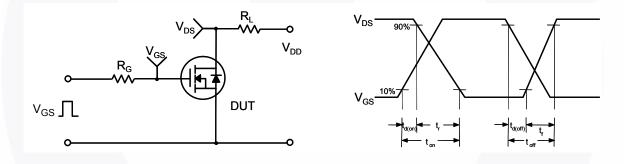
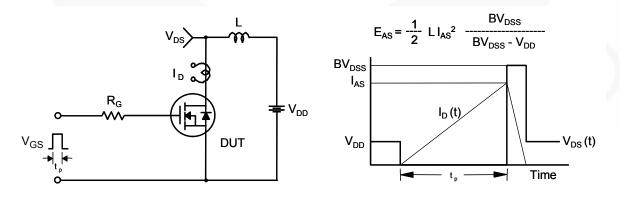


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



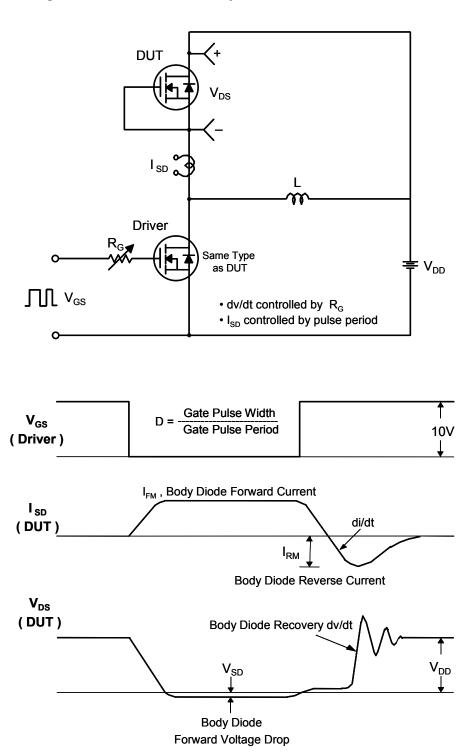


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

Mechanical Dimensions

TO-252 3L (DPAK)

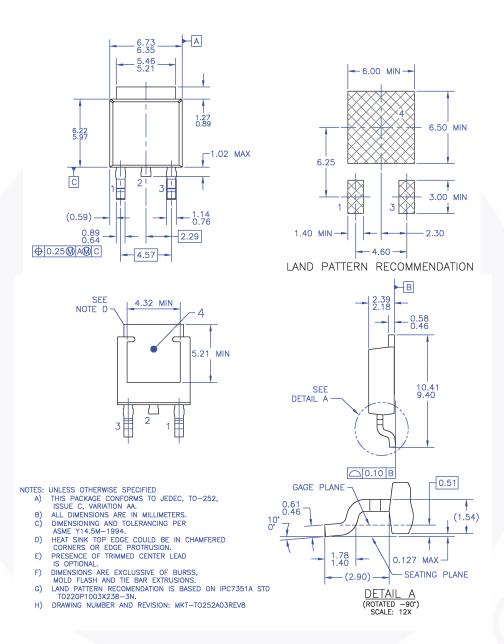


Figure 16. TO252 (D-PAK), Molded, 3 Lead, Option AA&AB

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Dimension in Millimeters





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